Search Notes

Application/Control No	. Applicant(s)/Patent under Reexamination		
10/525,537	KOBAYASHI, HISASHI		
Examiner	Art Unit		
Brian Nash	3721		

SEARCHED					
Class	Subclass	Date	Examiner		
227	131,129, 124,153, 155,5,6,7	3/13/2006	BN		
227	108,110,	3/13/2006	BN		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
227	US PGPub	6/9/2006	BN		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
227 (patents only) text, IDS, inventor search - via EAST - updated 6/9/2006	6/9/2006	BN		
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